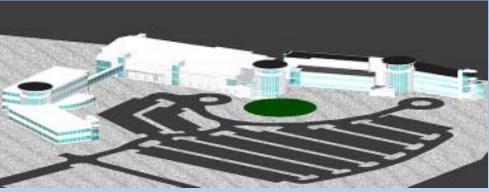


Feasibility of a SOFC Stack Integrated Optical Chemical Sensor







Michael A. Carpenter School of NanoSciences and NanoEngineering University at Albany, Albany, NY 12203





Outline

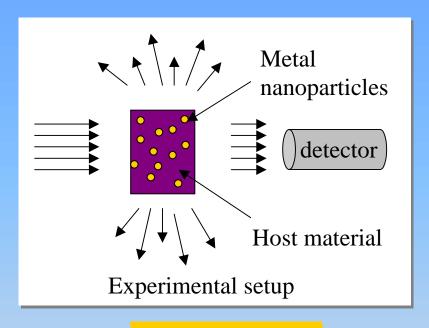
- •Sensor Introduction and Material Set Properties
- Deposition
- •Off-line optical interrogation
- Characterization
- Testing
- Theory
- Conclusions
- •Future Work





Surface Plasmon Resonance band Based Sensor for SOFC

- •Material set is stack integratable
 - •YSZ matrix with embedded Pd, Au, Pt nanoparticles
- •Monitor SPR changes as function of H₂, H₂S & CO and temperature
- •All optical technique; intrinsically safe
- •Material set is also compatible with Vision 21 initiatives



Stack Operating Temperature (°C)

600-1000



<u>Y</u>

Optical Properties of Metals

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• Drude theory alone is not sufficient to predict optical properties of metals, need to add in Lorentz oscillators for bound electrons

$$\varepsilon = 1 - \frac{\omega_{pe}^{2}}{\omega^{2} + i\gamma_{e}\omega} + \sum_{j} \frac{\omega_{pj}^{2}}{\omega_{j}^{2} - \omega^{2} - i\gamma_{j}\omega}$$

free electrons bound electrons

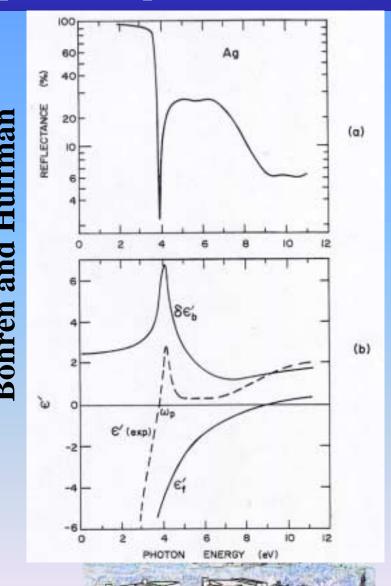
ε: dielectric function V: volume of the particle

 γ : damping factor q, κ : shape factors

 ω_p : plasma frequency k: wavenumber

 ω_i : resonant frequency of bound electrons

- The real portion, (free electrons) of the dielectric function for metal nanoparticles takes negative values above certain wavelengths
- Plasmon resonance shifted to higher wavelengths(lower energy)

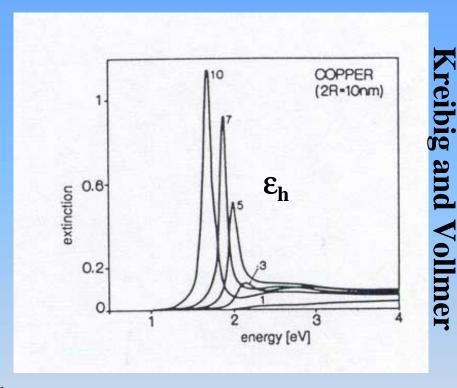




•SPR bands can be enhanced or shifted to lower energies by embedding nanoparticles in an oxide matrix

$$\alpha = \frac{V}{3q} \left\{ \frac{\varepsilon_m - \varepsilon_h}{\varepsilon_m + \kappa \varepsilon_h} \right\}$$

Polarizability (α) of a particle (ϵ_m) of arbitrary shape in host medium (ε_h), q and κ are shape factors:

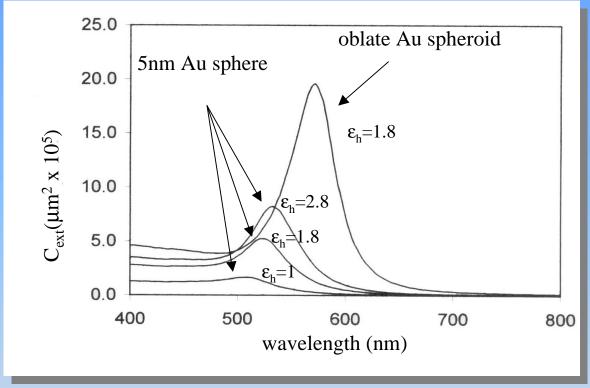


Extinction cross section

$$C_{ext} = k \operatorname{Im}\{\alpha\} + \frac{k^4}{6\pi} |\alpha|^2$$







D. L. Feldheim, C. A. Foss, 2002

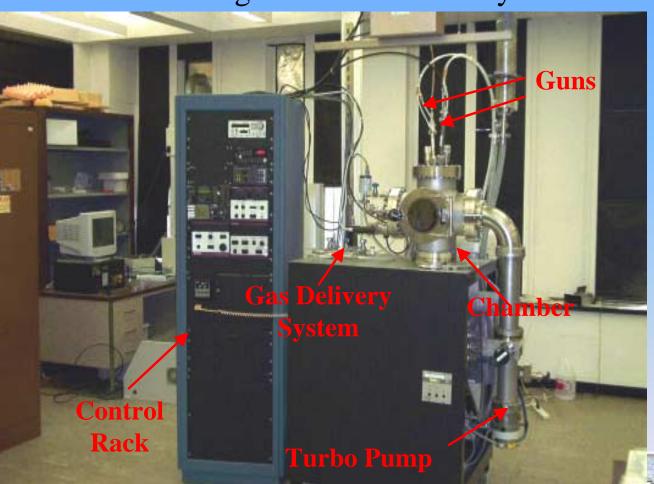
- The plasmon resonance extinction maximum can be shifted by changing the shape and/or the environment of the metal nanoparticle
- Will also be sensitive to the surrounding chemical environment





Physical Vapor Deposition

Dual Target Confocal PVD System

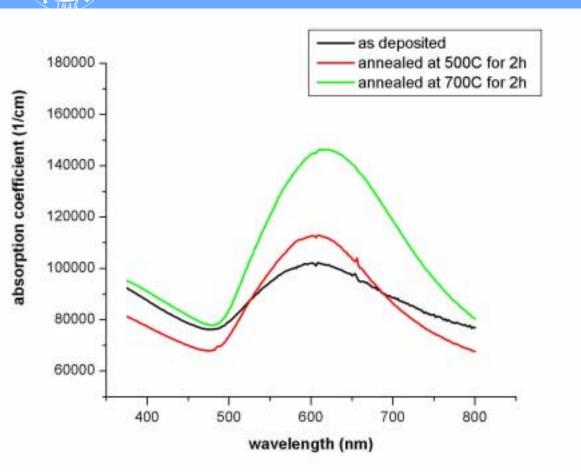


Deposition Parameters

- Pressure: 5mTorr
- Ar flow: 5sccm
- RF Power: 300Watts
- DC Power: 30Watts
- Deposition time: 10min.
- Substrates: glass/sapphire/silicon
- Thickness: 100nm

Off-line Optical Analysis of Films

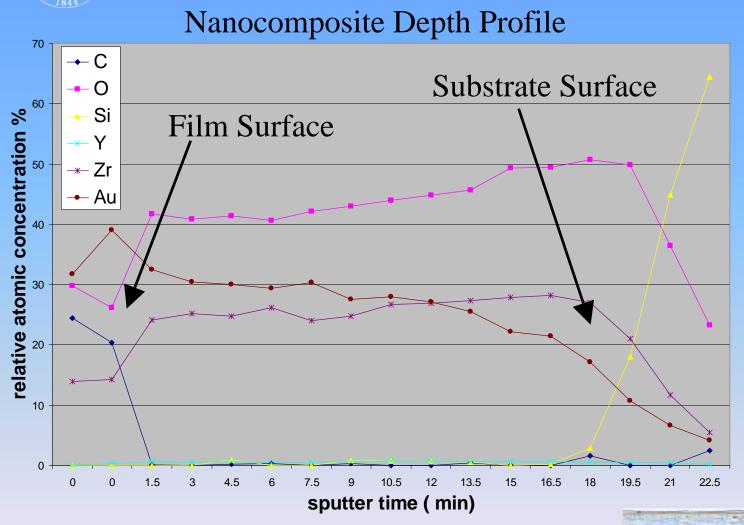
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- •100nm Film on Sapphire
- Analyzed using an Hewlett PackardSpectrometer
- Annealed under Argon and then subsequently analyzed
- •Intensity increase and shift to larger wavelengths indicates nanoparticle growth



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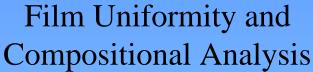


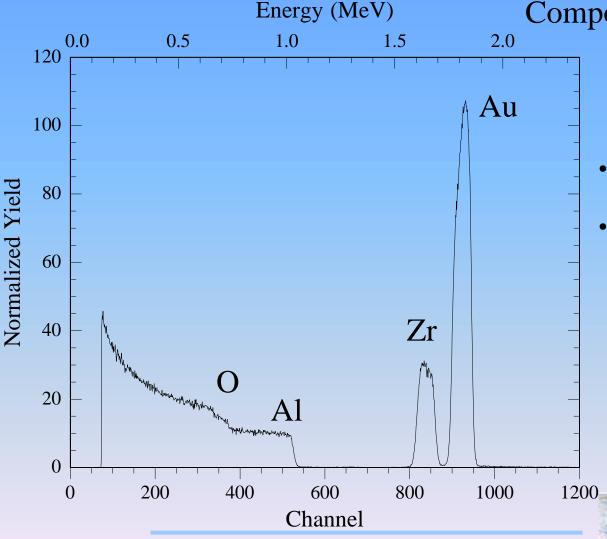
- 100nm thick film, as deposited on silicon
- Carbon surface contamination
- Film composition is uniform to 10%



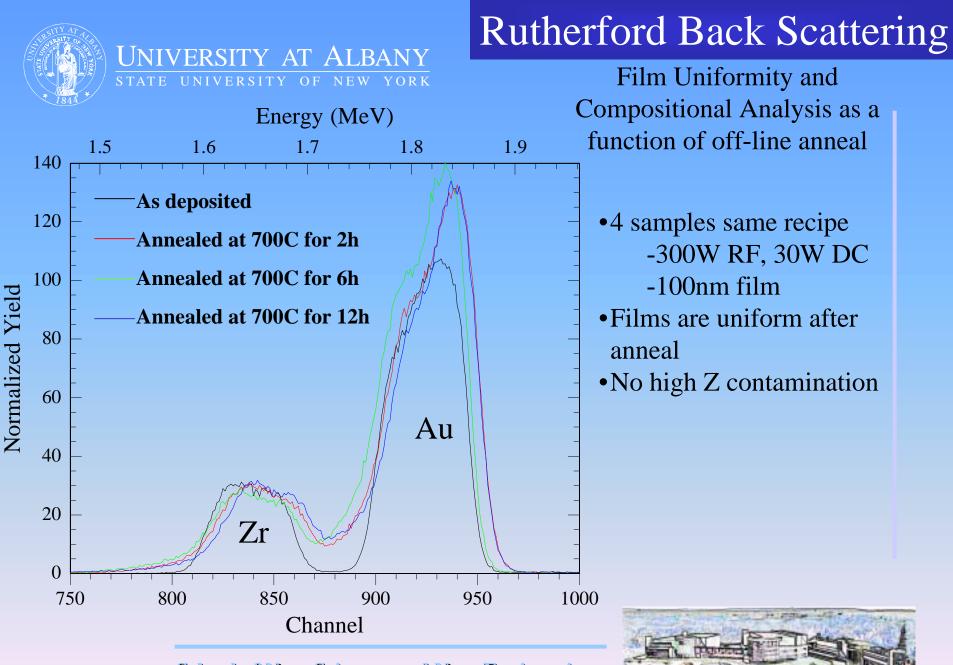


Rutherford Back Scattering



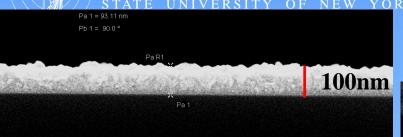


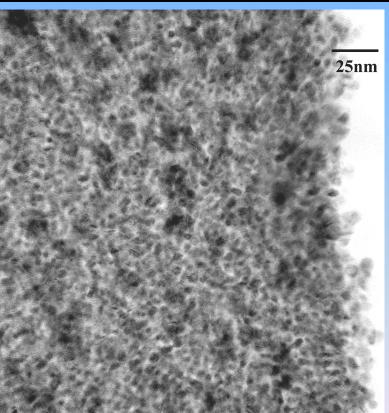
- 100nm film, as deposited on sapphire
- FWHM of both Au and Zr peaks are the same. Au and Zr are uniformly deposited throughout the film.



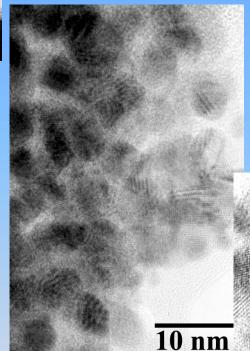
SEM/TEM Analysis of Films







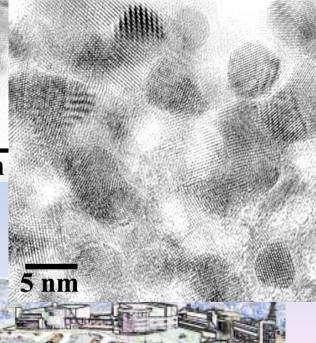
•SEM cross section of 100nm film on glass



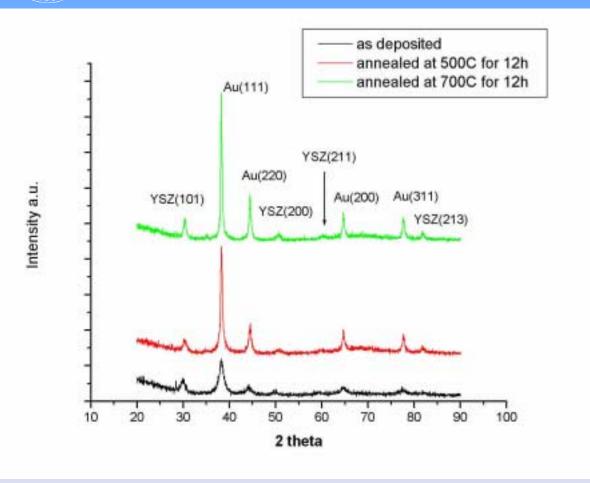
- TEM analysis of an as deposited 30nm film
- Sized 50 particles: 4.7nm±0.9nm

•Annealed sample to 500°C for 2 hrs

•Sized 50 particles: 5.2nm ±0.7nm



X-ray Diffraction Analysis



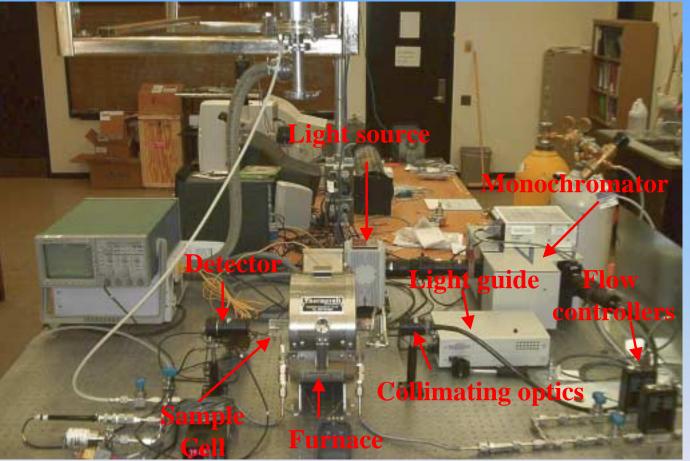
- •Crystal character increases with thermal anneal
- •Grain size analysis is in progress



High Temperature Optical Bench

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In-situ optical analysis(absorption) of nanocomposite



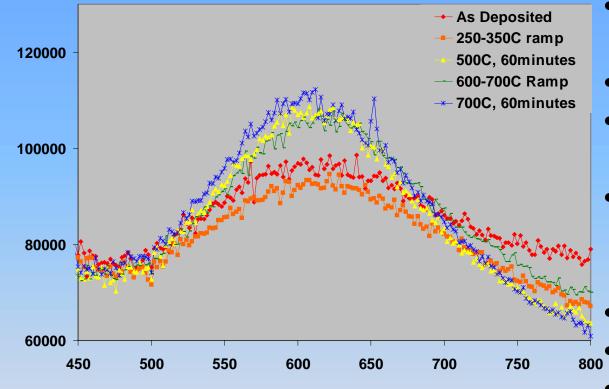
- •5J Xe flashlamp
- •Oriel MS257 monochromator
- •Si photodiode
- •Oven: up to 1200°C
- Quartz sample cell
- Macor sample holder
- •1sccm gas flow -N₂, 100ppm CO in N₂, air





In-situ Optical Analysis of Nanocomposite Films





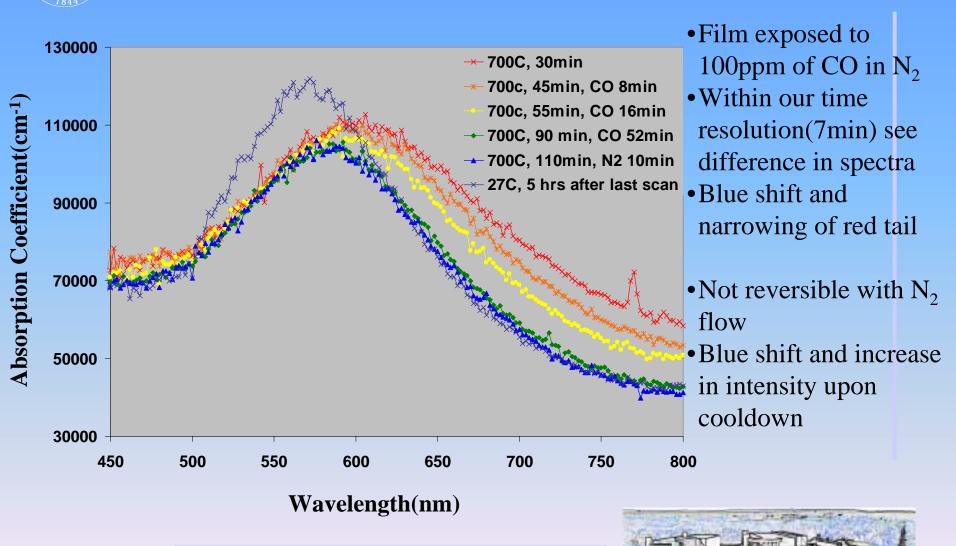
- 100nm film on sapphire
- 1L/min of nitrogen
- Initial decrease in intensity
- Blue shift and increase in the SPR band
- FWHM decrease
- Decrease in dielectric
 - Increase in particle numbers



Wavelength(nm)

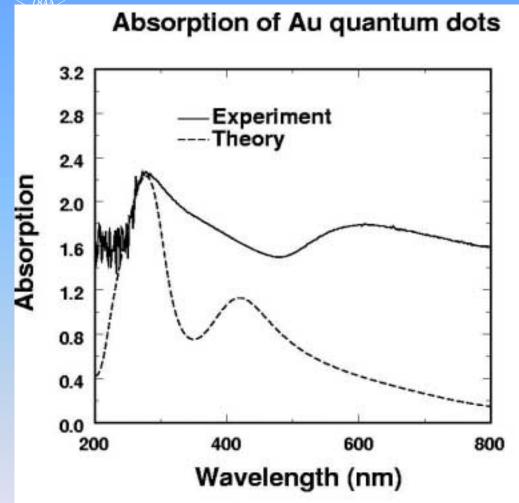


In-Situ Analysis as Function of Temperature and CO Exposure





Simple Theory of Classical Scatterers in a Thin Film



- Simplest starting point: classical spherical scatterers with bulk gold properties.
- Nanoparticles in dielectric thin film.
- Results qualitatively correct.
- Quantum polarizability will improve results.
- Dielectric surroundings and geometry (thin film) have important effect on absorption.



Conclusions

- •We are able to deposit nanocomposite thin films of Au nanoparticles in a YSZ matrix
- •We have developed a high temperature in-situ absorption cell system for optical analysis of materials
- SPR Bands are thermally stable once reach given temperature
 Do see a blue shift and intensity increases upon cooldown, but repeated heat treatments to working temperature produces repeatable bands
- •Have shown that SPR bands are sensitive to 100ppm of CO in nitrogen



Future Work



- •Optimize deposition routine for maximization of SPR signal and narrow bandwidth
- •Perform experiments in presence of O₂ and H₂O
- Calibrate response as function of CO concentration(1ppm to % levels)
- •Extend to deposition and testing of Pd and Pt nanocomposites(perform testing against CO and H₂)
- Theoretical calculations will be used to help determine if response is due to nanoparticle (size or shape) or to modifications in surrounding dielectric.

Future Phases

- •Integrate in-situ FTIR measurements to probe mechanism
- •Improve time resolution to seconds time scale by modifying optical bench to include CCD detector
- Industrial outreach through current and future SOFC partners







George Sirinakis(Ph.D student)

Dr. James Raynolds(SNN professor)

Dr. Kathleen Dunn(SNN professor)

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